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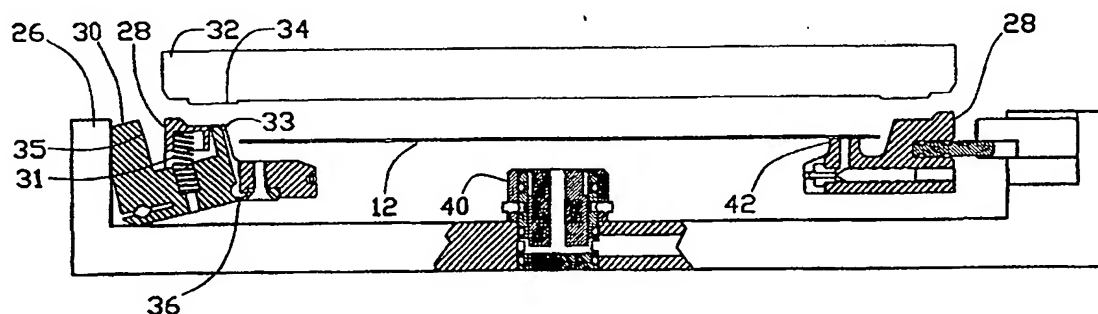
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(54) Title: ACCURATE POSITIONING OF A WAFER



(57) Abstract

A load station (18) is used in a planarizing machine to perform several useful functions related to handling of a wafer (12). By centering the wafer with respect to a spindle carrier (20) the load station interrupts the accumulation of positional errors. The load station never makes solid contact with the wafer, but instead the wafer is continually levitated on three cushions of water that are directed upwardly against the lower face of the wafer. The presence of the wafer partially impedes the flow of water from the nozzles (42, 44, 46) used for levitation causing an increase in the water pressure immediately upstream of the nozzles. This increased pressure is sensed and used as an indicator of the presence of a wafer at the load station. The load station further includes a nozzle (40) that directs a stream against the lower side of the wafer so as to elevate the wafer from the load station into the spindle carrier.

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ACCURATE POSITIONING OF A WAFER

DESCRIPTION

Technical Field

The present invention is in the field of semiconductor manufacturing and more specifically relates to improvements in apparatus for handling semiconductor wafers as they are carried through a planarizing machine.

5 Background Art

As supplied to the planarizing machine, the surface of a wafer may exhibit departures from flatness. Typically, 25 wafers are loaded into a cassette which is hand carried to a complex machine called a planarizer. The purpose of the planarizer is to render the front surface of the wafer flat to within a fraction of a micron. After each
10 wafer has been rendered flat, the planarizer inserts it into a cassette. When the cassette is full, it may be removed from the planarizer and transported to any of a number of other processing machines.

The present invention cannot be fully appreciated without an understanding of the operation of the planarizer. Once the cassette containing typically 25 pre-processed
15 wafers has been inserted into the planarizer, the operation of the planarizer in processing the wafers is completely autonomous. The operations are carried out under control of a computer that controls the application of power to various actuators in response to sensed inputs in a time-coordinated manner. In order for its lengthy program of operations to be carried out without mishap, it is important that means be
20 provided to interrupt the accumulation of positional errors. It can also be appreciated that the wafers must be handled carefully to avoid scratching the processed surfaces which are so fragile that they are never again touched by human hands.

The present invention can best be understood by following a typical wafer as it is moved through the planarizer. The wafer is extracted from the cassette by a
25 portion of the planarizer called a robot. The robot carries the wafer to a fixed location known as the load station. After the robot has deposited the wafer at the load station

and has moved out of the way, a different part (called a spindle carrier) moves into position above the wafer and acquires it. The spindle carrier transports the wafer to a rotating polishing platen and rotates the wafer while holding it in contact with the rotating polishing platen until the wafer has been rendered flat. Thereafter, the spindle
5 lifts the wafer from the polishing platen and transports it back to the load station where the wafer is rinsed. After the spindle carrier has deposited the wafer at the load station and has moved out of the way, the robot picks up the polished wafer and carries it to a cassette and deposits the wafer in the cassette. Throughout these operations, the wafer is maintained in a horizontal position with the side that is to be polished facing
10 downward. That downward facing side of the wafer is also referred to as the front side of the wafer. The path of an individual wafer through the planarizer will be depicted in greater detail below.

Upon reflection it will be seen that the main purpose of the load station is to accurately center the wafer into the carrier notwithstanding the errors in their relative
15 positions as they enter the load station.

In addition to centering the wafer with respect to the carrier, the load station performs a number of useful ancillary functions. The load station includes provision for sensing the presence of the wafer at the load station, for rinsing the wafer, for lifting the wafer into the carrier, and for supporting the processed wafer on cushions of water
20 to avoid direct contact. Thus, the load station serves several other functions in addition to centering the wafer with respect to the carrier.

Disclosure of the Invention

A wafer that has been deposited at the load station reposes in a horizontal attitude on cushions of purified water that are produced by three upwardly-directed
25 nozzles affixed to a load ring, which is free to slide laterally on a horizontal base. Initially, the wafer is not centered within the load ring and the load ring is not centered with respect to the vertical axis of the spindle carrier. One objective of the present invention is to eliminate these centering errors.

In accordance with the present invention this is accomplished through the
30 provision of a load ring assembly that is driven by the spindle carrier as it descends

from an initial position above the load ring assembly. The load ring assembly includes, in addition to the load ring, at least three centering tabs spaced around the periphery of the load ring and hinged to the load ring by hinges having axes that are horizontal and tangential to the load ring. These centering tabs are yieldingly biased to an open position in which certain inwardly-facing surfaces of the centering tabs diverge upwardly. As the spindle carrier descends, it pushes downwardly on an upper surface of the load ring, overcoming the biasing force to cause the centering tabs to pivot in such a way that the aforementioned inwardly-facing surfaces converge to a vertical attitude. As the inwardly-facing surfaces converge, they contact the periphery of the spindle carrier, centering the load ring with respect to it, and they also contact the edge of the hovering wafer, centering the wafer with respect to the load ring. Because the wafer is centered with respect to the load ring and the load ring is centered with respect to the spindle carrier, it follows that the wafer is centered with respect to the spindle carrier.

15 In accordance with the present invention, the upwardly-directed nozzles that form the liquid cushions on which the wafer reposes are affixed to the load ring, so as not to disturb the cushions as the load ring is pushed downward by the descending spindle carrier.

20 The presence of the wafer on the liquid cushions produced by the upwardly-directed nozzles slightly impedes the flow of the purified water from the nozzles, causing an increase in the pressure in the conduits that feed the nozzles. In accordance with the present invention, this pressure increase is sensed by a pressure sensor and serves to indicate the presence of a wafer. When the wafer is absent, a lower pressure prevails, and the sensed lower pressure serves to indicate the absence of a wafer from the load station.

25 After the above-described centering procedure has been completed, the wafer must be acquired by the spindle carrier and rinsed. In accordance with the present invention, this is accomplished by the provision of a unique upwardly-directed nozzle located below the wafer and centered with respect to it. A spool-like portion of this nozzle discharges purified water against the underside of the wafer, rinsing it from the center outwardly, and lifting the wafer on a cushion of purified water. The spool-like

portion then rises, carrying the wafer upward on the liquid cushion until the wafer comes into contact with a vacuum pad located on the underside of the spindle carrier, where the wafer is acquired by the suction of the vacuum pad, which holds the wafer to the spindle carrier.

5 The novel features which are believed to be characteristic of the invention, both as to organization and method of operation, together with further objects and advantages thereof, will be better understood from the following description considered in connection with the accompanying drawings in which a preferred embodiment of the invention is illustrated by way of example. It is to be expressly understood, however,
10 that the drawings are for the purpose of illustration and description only and are not intended as a definition of the limits of the invention.

Brief Description of the Drawings

Figure 1 is a diagram showing the use of a robot to remove a wafer from a cassette;

15 Figure 2 is a diagram showing the robot placing a wafer on the load station;

Figure 3 is a diagram showing the spindle carrier after it has moved to a position directly above the load station;

20 Figure 4 is a diagram showing the spindle carrier descending onto the load station and acquiring the wafer;

Figure 5 is a diagram showing the spindle carrier transporting the wafer to a polishing platen;

Figure 6 is a diagram showing the spindle carrier holding the wafer on the polishing platen;

25 Figure 7 is a diagram showing the spindle carrier transporting the polished wafer to the load station;

Figure 8 is a diagram showing the spindle carrier depositing the polished wafer on the load station;

Figure 9 is a diagram showing the robot removing the polished wafer from the load station after the spindle carrier has returned to its home station above the polishing platen;

Figure 10 is a diagram showing the robot placing the polished wafer into
5 a cassette;

Figure 11 is a top plan view of the load station of Figures 1-4;

Figure 12 is a side elevational view in cross section through the load station of Figure 11, in the direction 12-12 indicated in Figure 11, showing the configuration of the parts when the carrier first makes contact with the centering
10 apparatus of the load station;

Figure 13 is a side elevational cross sectional view through the load station of Figure 11 showing the positions of the parts at the conclusion of the centering operation;

Figure 14 is a side elevational cross sectional view through the load
15 station of Figure 11 showing the center nozzle actuated to lift the wafer into the carrier;

Figure 15 is a side elevational cross sectional view through the load station of Figure 11 showing the center nozzle rinsing the polished wafer;

Figure 16 is a hydraulic diagram of the hydraulic system used for hovering of the wafer and sensing its presence;

Figure 17 is a side elevational view of an alternative embodiment of the centering apparatus showing its configuration at the instant the carrier portion of the spindle carrier first makes contact with the centering apparatus; and,
20

Figure 18 is a side elevational view of the alternative embodiment of the centering apparatus of Figure 17 showing its configuration when the spindle carrier is
25 in the lowest position with the wafer centered in the carrier.

Best Mode for Carrying Out the Invention

The present invention includes a series of operations carried out by a planarizing machine on a wafer that is to be planarized. Generally, the front surface, on which the electronic circuitry will be deposited is not as flat as required. The overall

purpose of the planarizing machine is to render the front surface of each wafer as flat as possible.

The wafers are carried to the machine in an incoming cassette 16 in which the wafers are temporarily stored in a stacked configuration. The incoming cassette is
5 inserted into the planarizing machine, and thereafter the machine processes the wafers autonomously, presenting the processed wafers in an outgoing cassette 24 of Figure 10, which the operator removes from the machine. A typical cassette has a capacity of 25 wafers.

Figures 1-10 form a series showing schematically the path of a wafer as it
10 progresses through the planarizing machine.

As shown in Figure 1, a robot 14 removes the upper-most wafer 12 from the incoming cassette 16 and transports the wafer to a load station 18. In a preferred embodiment, the robot holds onto the wafer by applying suction to the upper surface of the wafer, also called the back side of the wafer, which is not the surface that is to
15 be rendered flat.

As shown in Figure 2, the robot 14 deposits the wafer 12 onto the load station 18. The robot then moves to an out-of-the-way station leaving the wafer reposing on a cushion of purified water provided by the load station, as will be described below.

Next, as shown in Figure 3, the spindle 20 moves into a position directly above
20 the load station 18, and as indicated in Figure 4, the spindle is lowered onto the load station 18. As will be described below, the descending motion of the spindle 20 centers the load station 18 with respect to the spindle carrier 32 and simultaneously centers the wafer 12 with respect to the spindle carrier 32. At this juncture, an upwardly-directed jet of purified water directed against the lower face of the wafer lifts the centered wafer
25 into contact with the carrier, which then acquires the wafer through the use of a vacuum system of the type described in U.S. Patent No. 5,423,716 issued June 13, 1995 to Alan Strasbaugh for WAFER-HANDLING APPARATUS HAVING A RESILIENT MEMBRANE WHICH HOLDS WAFER WHEN A VACUUM IS APPLIED, in U.S. Patent No. 5,449,316 issued September 12, 1995 to Alan
30 Strasbaugh for WAFER CARRIER FOR FILM PLANARIZATION, and in U.S. Application Serial No. 08/971,642 filed November 17, 1997 by Salman M. Kassir and

Thomas A. Walsh for GRINDING PROCESS AND APPARATUS FOR PLANARIZING SAWED WAFERS. The disclosures of U.S. Patents No. 5,423,716 and 5,449,316 are incorporated herein by reference.

5 Having thus acquired the wafer, the spindle 20 lifts the wafer from the load station 18 and carries it to the polishing platen 22. The spindle 20 rotates the wafer 12 about a vertical axis that is displaced from the vertical axis about which the polishing platen rotates, as is known in the art. Figure 6 shows the carrier holding the wafer 12 against the polishing platen 22, whereby the lower surface of the wafer is polished flat.

10 After the polishing has been completed, the planarized wafer is transported by the spindle 20 to the load station 18 and deposited there as shown in Figures 7 and 8. Thereafter, the spindle moves to an out-of-the-way position and the wafer is rinsed by the load station 18. Following this rinsing, the wafer is acquired by the robot 14 and transported to an outgoing cassette 24, as shown in Figures 9 and 10, respectively. Thereafter, the planarizing machine repeats the process with the next wafer which is
15 upper-most in the incoming cassette 16 of Figure 1.

More recent embodiments of the planarizing machine employ multiple polishing platens, robots, spindles, and load stations permitting two or more wafers to be processed simultaneously with the operations performed in parallel or staggered for maximum efficiency.

20 A portion of the spindle 20 called the carrier 32 is a ring-shaped part that encircles the wafer so as to retain the wafer in the spindle during the polishing process by preventing the wafer from slipping out sideways. The radial spacing between the circumference of the wafer and the inner edge of the carrier is typically a fraction of a millimeter. One of the most significant problems solved by the load station 18 is
25 centering of the wafer with respect to the carrier ring to such a close tolerance. The initial placement of the wafer onto the load station, as indicated in Figure 1, includes positional errors, and likewise, the positioning of the spindle 20 above the load station, as in Figure 3, is also subject to position errors. Without some way of eliminating these various lateral position errors, it would be impossible for the wafer to be acquired
30 within the carrier 32 of the spindle 20.

In the preferred embodiment the centering action of the load station is accomplished in a manner which will now be described in connection with Figures 11, 12, and 13. The load ring assembly of Figure 11 lies horizontally within a pan-like base 26. The load ring 28 is not rigidly attached to the base 26 and, in fact is capable of limited lateral sliding motion with respect to the base 26. A number, typically six, of centering tabs, of which the tab 30 is typical, are spaced around the circumference of the load ring 28. These tabs are pivotably attached to the load ring, each pivoting about its own horizontal axis that is tangent to the load ring. The tabs pivot from an unloaded position shown in Figure 12 to a loaded position shown in Figure 13. In the unloaded condition, the tabs are biased to the position shown in Figure 12 by a helical spring 31, and the tab bends at a living hinge 36.

Figure 12 shows the load station after the wafer has been deposited on it by the robot 14, but before the spindle carrier 32 has descended. Figure 13 shows the load station after the spindle has descended to its lowest extent. Note that Figure 12 is a view in the directions 12--12 shown in Figure 11.

When first deposited onto the load station 18 the wafer 12 is unlikely to be concentric with the carrier 32 of the spindle 20, and as seen in Figure 12, clearance is provided for lateral movement of the wafer. The wafer is levitated on cushions of purified deionized water that emerge under low pressure from the nozzles 42, 44, 46. In the preferred embodiment, there are three such nozzles, and the presence of the water flowing between the body of the nozzle 42, 44, 46 and the wafer prevents contact of the nozzle with the lower side of the wafer.

As the spindle carrier is lowered onto the load station 18 as shown in Figure 4, the horizontal lower surface 34 of the carrier 32 pushes downwardly against the top horizontal surface of the load ring 28 overcoming the biasing force of the helical spring 31 causing a first inward-facing surface 33 of the centering tab to swing radially inward until the inward-facing surface makes contact with the edge of the wafer 12. Concurrently, the pivoting of the centering tab brings a second inwardly facing surface 35 into contact with the circumference of the carrier 32. The carrier 32 is not free to move laterally, and therefore the load ring shifts laterally in an effort to center itself with respect to the carrier. At the conclusion of the downward motion of the spindle,

the load ring 28 is centered with respect to the carrier 32, and the wafer is centered with respect to the load ring; therefore, the wafer is centered with respect to the carrier. Immediately thereafter, an upwardly-directed jet of water from the nozzle 40 elevates the wafer 12 into the carrier 32 and holds it in that position long enough for
5 the vacuum system of the spindle carrier to acquire the wafer. Having thus acquired the wafer, the spindle then transports the wafer to the polishing platen 22 as shown in Figure 5.

To avoid the possibility of accidentally damaging the front (lower) face of the wafer 12, both before and after it has been planarized, the wafer is always supported
10 while at the load station 18 on three cushions of purified and deionized water. These cushions of water flow between the underside of the wafer and the upper end of the nozzles 42, 44 and 46 seen in Figure 11. As best seen in Figures 12 and 13, these nozzles are attached to the load ring 28, so that as the load ring is pushed downwardly by the spindle, the nozzles 42, 44 and 46 move downward with the load ring, thereby
15 continuing to support the wafer.

Figure 16 is a hydraulic diagram showing how the nozzles are connected to a supply main 48. It has been found that a relatively low volumetric flow rate is adequate to prevent the wafer 12 from contacting the nozzles.

The present inventors have discovered that the nozzles 42, 44 and 46 can
20 perform another useful function, in addition to levitating the wafer. The presence of the wafer as it is being levitated above the nozzles increases the resistance of each nozzle to the outflow of water. Clearly, if each nozzle were completely closed off, the pressure in the branches 50, 52 and 54 would become equal to the supply pressure. At the other extreme, if the nozzles 42, 44 and 46 offered no resistance to the flow, then
25 the pressure in the branches 50, 52 and 54 would be considerably less than the supply pressure. The present inventors saw that this effect can be used to sense the presence of the wafer as it rests on the cushion of water between the tops of the nozzles and the lower side of the wafer. To implement this, the inventors have inserted a pressure sensor 56 in the branch 54 as shown in Figure 16. The inventors have found that it is
30 beneficial to insert a flow restrictor 58 in the branch 54 upstream of the pressure sensor

56. Valves 60 and 62 in the branches 50 and 52 respectively permit equalization of the flow through the nozzles.

Knowledge of whether a wafer is reposing on the load station 18, obtained by the pressure sensor 56, is useful in determining what the spindle 20 should do in the situation illustrated in Figure 4 and in the situation illustrated in Figure 8. The presence of a wafer on the load station in Figure 3 results in the spindle descending to the position shown in Figures 4 and 13 so as to acquire the wafer. In contrast, the absence of a wafer on the load station in Figure 8 results in the spindle descending only far enough to deposit the wafer on the nozzles 42, 44 and 46 as shown in Figure 12.

Figures 12, 13, and 14 show cross sectional views of nozzle 40. It will be recalled that this nozzle provides a stream of water directed upward toward the lower face of the wafer 12 for the purpose of elevating the wafer into contact with a vacuum pad within the spindle carrier, whereby the carrier acquires the wafer from the load station. As best seen in Figure 14, the nozzle 40 includes a cylinder 64 within which a spool 66 is disposed in a loose sliding fit. This permits the spool 66 to move upward from the position shown in Figure 13 to the position shown in Figure 14 wherein a shoulder 68 on the spool is stopped by a flange 70. The spool 66 includes a central passage 72 through which the purified water is discharged.

After the carrier 32 is lowered into the load station to the position shown in Figure 13, the upward flow of water out of the top of the spool 66 is partially impeded by the presence of the wafer. This causes an increase in pressure in the chamber immediately below the spool, thereby pushing the spool upwards within the cylinder 64 to the position shown in Figure 14. At no time does the spool 66 touch the wafer (because of the water cushion), but as the wafer moves upward the spool is able to keep up with it, thereby maintaining an upward force on the wafer that pushes the upper surface of the wafer against a vacuum pad within the carrier, and holding the wafer against the pad until the vacuum causes the wafer to be secured to the carrier.

The relatively strong upward stream discharged by the nozzle 40 rinses the wafer from the center outwardly seen in Figure 15. The spool never contacts the wafer after the wafer has been polished.

Figures 17 and 18 show an alternative embodiment of the pivoting fingers 30 of Figures 12 and 13. Figure 17 shows the configuration after the wafer 12 has been deposited but before the centering process has begun. Figure 18 shows the configuration at the conclusion of the centering process.

5 As the spindle 20 descends from the position shown in Figure 17 to the position shown in Figure 18, the pivoting body 76 is forced to rotate clockwise (as seen in the drawings) until the surface 76 contacts the cylindrical outer surface of the carrier 78 thereby centering the load ring with respect to the carrier, while simultaneously, the surface 80 contacts the edge of the wafer 12 so as to center the wafer with respect to the load ring. As shown in Figure 18, at the conclusion of the centering process the load ring is centered with respect to the carrier and the wafer is centered with respect to the load ring, and therefore the wafer must be centered with respect to the carrier.

Thus, there has been described a very useful load station for handling wafers within a planarizing machine. The load station interrupts the accumulation of positional errors by centering the wafer with respect to the carrier that is acquiring the wafer. The acquisition is accomplished without touching the front side of the wafer by use of a novel nozzle that elevates the wafer into the carrier by directing a jet of water against the front side of the wafer. At no time does the wafer actually make solid contact with the load station. Instead, the wafer is always levitated on three fountains of water.

15 Back pressure caused by the wafer impeding the flow of water from these fountains is sensed and the sensed signal is used to indicate the presence of a wafer on the load station.

The foregoing detailed description is illustrative of one embodiment of the invention, and it is to be understood that additional embodiments thereof will be obvious to those skilled in the art. The embodiments described herein together with those additional embodiments are considered to be within the scope of the invention.

25

Industrial Applicability

The load station of the present invention is an essential part of a planarizing machine that is capable of rendering flat the front surface of a wafer to within a fraction of a micron to meet the demands of the semiconductor industry.

CLAIMS

1. A load station for handling wafers, having the capability of bringing the center of a circular wafer that is maintained in a horizontal plane into coincidence with the axis of an overhead spindle carrier, which axis is perpendicular to the horizontal plane, where the initial position of the wafer in the horizontal plane is subject to two-dimensional position errors, and where the spindle carrier moves downward along its axis from an upper initial position to a lower final position, and where the spindle carrier has an underside that includes a vacuum pad for use in acquiring the wafer, the load station characterized by:
- 5 a base having a horizontal upper surface;
- 10 a load ring assembly slidably resting on the upper surface of the base and including
- a load ring initially disposed in a first horizontal plane spaced above the upper surface of the base and having a center;
- 15 at least three centering tabs spaced around the circumference of the load ring;
- hinge means connecting the centering tabs to the load ring for pivoting motion about horizontal axes that are tangent to the load ring, said hinge means located equidistant from the center of the load ring;
- 20 biasing means operatively connected to the load ring and to the centering tabs, yieldably urging the centering tabs to an initial position in which portions of the centering tabs extend below the first horizontal plane and radially outward beyond the hinge means and bear on the horizontal surface of the base to
- 25 yieldably support the load ring in its initial position above the upper surface of the base;
- the load ring having a top surface against which the spindle carrier pushes as it moves downward, pushing the load ring downward from its initial position and overcoming the biasing means to

30 force the centering tabs to pivot from their initial positions and
to arrive at final positions when the spindle carrier and load ring
have reached their lower final positions;

35 said centering tabs having first inwardly facing surfaces extending
above the hinge means and through the horizontal plane in
which the wafer is maintained so as to pivot inwardly as the
load ring is forced downward by the descending spindle carrier,
the first inwardly facing surfaces pushing against the edge of the
wafer as the spindle carrier descends, to guide the wafer,
bringing its center into coincidence with the center of the load
40 ring;

45 said centering tabs having second inwardly facing surfaces extending
above the hinge means and above the first inwardly-facing
surfaces so as to pivot inwardly as the load ring is forced
downward by the descending spindle carrier, the second
inwardly facing surfaces pushing against the unyielding
50 periphery of the spindle carrier to slidably guide the load ring,
bringing its center into coincidence with the axis of the spindle
carrier;

55 so that, when the spindle carrier has descended to its lower final
position, the center of the wafer has been guided to the center
of the load ring and the center of the load ring has been guided
to the axis of the spindle;

 whereby, the center of the wafer has been brought into coincidence
with the axis of the spindle carrier through the use of the load
ring assembly.

2. The load station of Claim 1, having the further capability of maintaining the wafer in a horizontal plane without mechanically contacting the wafer, wherein the load ring assembly is further characterized by:

5 exactly three upwardly-directed nozzles affixed to the load ring at spaced locations; and,

means for supplying a pressurized fluid to each nozzle, the pressurized fluid flowing from the nozzles forming a separate cushion at each nozzle between the nozzle and the wafer;

10 whereby the cushions provide a stable three-point support for the wafer, prevent the wafer from coming into contact with the nozzles, maintain the wafer at a constant position with respect to the load ring as the load ring moves vertically, and permit friction-free lateral movement of the wafer as the wafer is being centered with respect to the load ring.

3. The load station of Claim 2 having the further capability of sensing the presence and absence of a wafer, wherein the means for supplying a pressurized fluid include:

5 a supply main;
branches connecting the supply main to each of the three nozzles; and,
a pressure sensor connected to one of the branches for sensing the pressure of the pressurized fluid in that branch;

whereby the presence or absence of a wafer in the load ring is indicated by the sensed pressure .

4. The load station of Claim 3 further including flow-limiting means inserted into each of the branches.

5. The load station of Claim 1 having the further capability of rinsing the wafer from the center outwardly and raising the wafer for acquisition by the spindle carrier, and further characterized by:

5 a hollow cylinder coaxial with the spindle carrier, having a closed lower end affixed to the base and having an upper end spaced below the wafer when the load ring is in its lower final position;

10 a spool having an upper end and a lower end and a central passage extending through it between the upper end and the lower end, the spool disposed within the hollow cylinder in a loose sliding fit for axial motion within the hollow cylinder from a lower position in which the upper end of the spool is spaced below the lowest position of the wafer and the lower end of the spool is spaced above the closed lower end of the hollow cylinder, to an upper position in which the upper end of the spool extends above the upper end of the hollow cylinder; and,

15 means for supplying fluid under pressure to the space between the lower end of the spool and the closed lower end of the hollow cylinder;

20 whereby, as the wafer is being lowered toward its lowest position, the pressurized fluid passes up through the central passage and is discharged from the upper end of the spool, but when the wafer reaches its lowest position it partially impedes the discharge, thereby increasing the pressure of the fluid in the hollow cylinder below the spool and applying an upward force on the spool sufficient to overcome its weight, causing the spool to rise from its lower position to its upper position and thereby to lift the wafer on a cushion of fluid that prevents contact between the spool and the wafer, whereby the wafer is raised into contact with the vacuum pad located on the underside of the spindle carrier, and whereby the wafer is rinsed from its center outwardly .

6. A load station for handling wafers, having the capability of bringing the center of a circular wafer that is maintained in a horizontal plane into coincidence with the axis of an overhead spindle carrier, which axis is perpendicular to the horizontal plane, where the initial position of the wafer in the horizontal plane is subject to two-dimensional position errors, and where the spindle carrier moves downward along its axis from an upper initial position to a lower final position, and where the spindle carrier has an underside that includes a vacuum pad for use in acquiring the wafer, the load station characterized by:

a base have a horizontal upper surface;

a load ring assembly slidably resting on the upper surface of the base and including

a load ring having a center;

at least three centering tabs spaced around the circumference of the load ring;

hinge means connecting the centering tabs to the load ring for pivoting motion about horizontal axes that are tangent to the load ring, said hinge means located equidistant from the center of the load ring;

biasing means operatively connected to the load ring and to the centering tabs, yieldably urging the centering tabs to initial positions in which portions of the centering tabs that are radially inward of the hinge means extend into the path of the descending spindle carrier, so that as the spindle carrier moves downward it pushes against these portions of the centering tabs and overcomes the biasing means to force the centering tabs to pivot from their initial positions and to arrive at final positions when the spindle carrier has reached its lowest final position;

said centering tabs having first inwardly facing surfaces extending above the hinge means and through the horizontal plane in which the wafer is maintained so as to pivot inwardly as the spindle carrier descends, the first inwardly facing surfaces

pushing against the edge of the wafer as the spindle carrier descends, to guide the wafer, bringing its center into coincidence with the center of the load ring;

35

said centering tabs having second inwardly facing surfaces extending above the hinge means and above the first inwardly facing surfaces so as to pivot inwardly as the spindle carrier descends, the second inwardly facing surfaces pushing against the unyielding periphery of the spindle carrier to slidably guide the load ring, bringing its center into coincidence with the axis of the spindle carrier;

40

so that, when the spindle carrier has descended to its lower final position, the center of the wafer has been guided to the center of the load ring and the center of the load ring has been guided to the axis of the spindle;

45

whereby, the center of the wafer has been brought into coincidence with the axis of the spindle carrier through the use of the load ring assembly.

7. The load station of Claim 1, having the further capability of maintaining the wafer in a horizontal plane without mechanically contacting the wafer, wherein the load ring assembly is further characterized by:

5 exactly three upwardly-directed nozzles affixed to the load ring at spaced locations; and,

means for supplying a pressurized fluid to each nozzle, the pressurized fluid flowing from the nozzles forming a separate cushion at each nozzle between the nozzle and the wafer;

10 whereby the cushions provide a stable three-point support for the wafer, prevent the wafer from coming into contact with the nozzles, and permit friction-free lateral movement of the wafer as the wafer is being centered with respect to the load ring.

8. The load station of Claim 7 having the further capability of sensing the presence and absence of a wafer, wherein the means for supplying a pressurized fluid include:

5 a supply main;
branches connecting the supply main to each of the three nozzles; and,
a pressure sensor connected to one of the branches for sensing the pressure of the pressurized fluid in that branch;

whereby the presence or absence of a wafer in the load ring is indicated by the sensed pressure.

9. The load station of Claim 8 further including flow-limiting means inserted into each of the branches.

10. The load station of Claim 6 having the further capability of rinsing the wafer from the center outwardly and raising the wafer for acquisition by the spindle carrier, and further characterized by:

5 a hollow cylinder coaxial with the spindle carrier, having a closed lower end affixed to the base and having an upper end spaced below the wafer;

10 a spool having an upper end and a lower end and a central passage extending through it between the upper end and the lower end, the spool disposed within the hollow cylinder in a loose sliding fit for axial motion within the hollow cylinder from a lower position in which the upper end of the spool is spaced below the wafer and the lower end of the spool is spaced above the closed lower end of the hollow cylinder, to an upper position in which the upper end of the spool extends above the upper end of the hollow cylinder; and,

means for supplying fluid under pressure to the space between the lower end of the spool and the closed lower end of the hollow cylinder;

15 whereby, after the wafer has been centered with respect to the spindle carrier, the pressurized fluid passes up through the central passage and is discharged from the upper end of the spool, but the wafer partially impedes the discharge, thereby increasing the pressure of the fluid in the hollow cylinder below the spool and applying an upward force on the spool sufficient to overcome its weight, causing the spool to
20 rise from its lower position to its upper position and thereby to lift the wafer on a cushion of fluid that prevents contact between the spool and the wafer, whereby the wafer is raised into contact with the vacuum pad located on the underside of the spindle carrier, and whereby the wafer is rinsed from its center outwardly.

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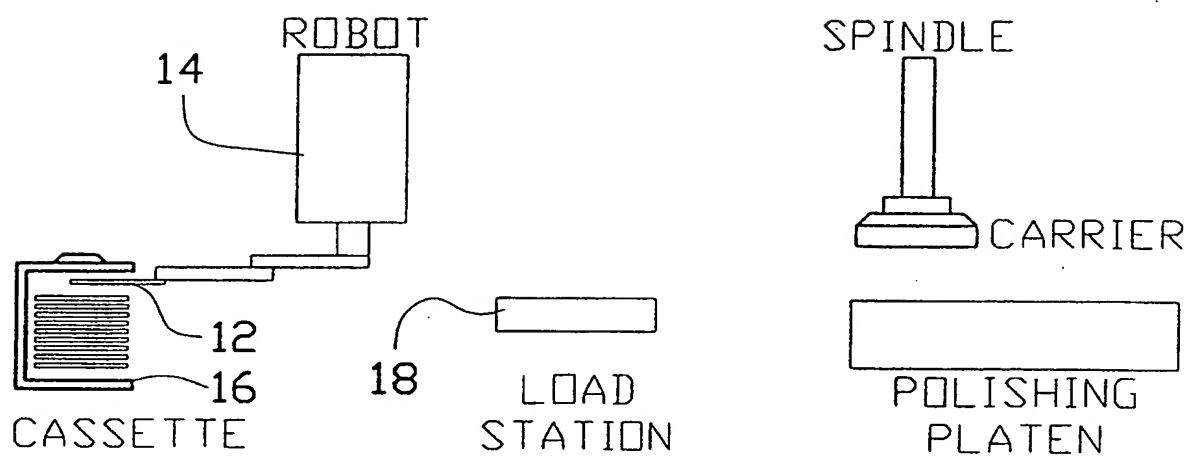


FIG. 1

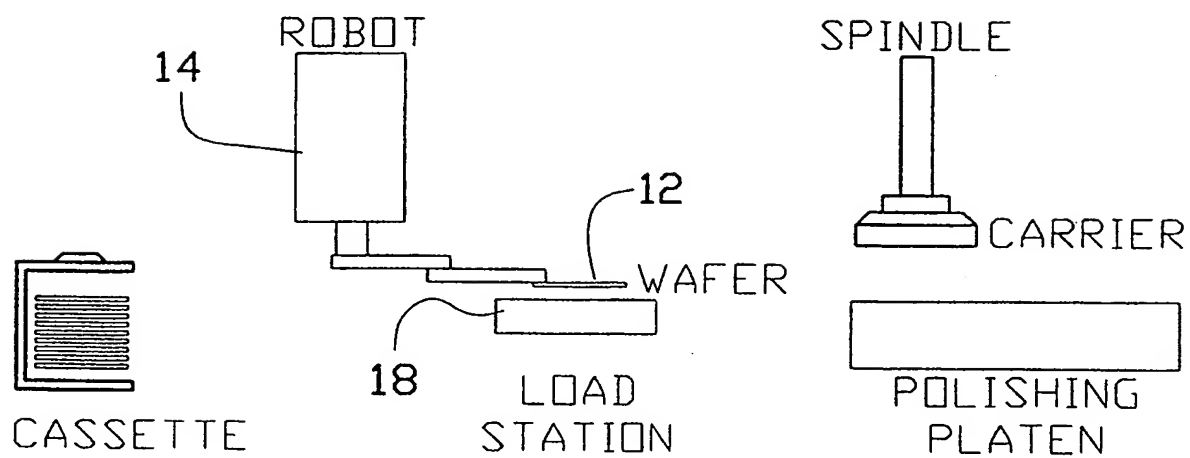


FIG. 2

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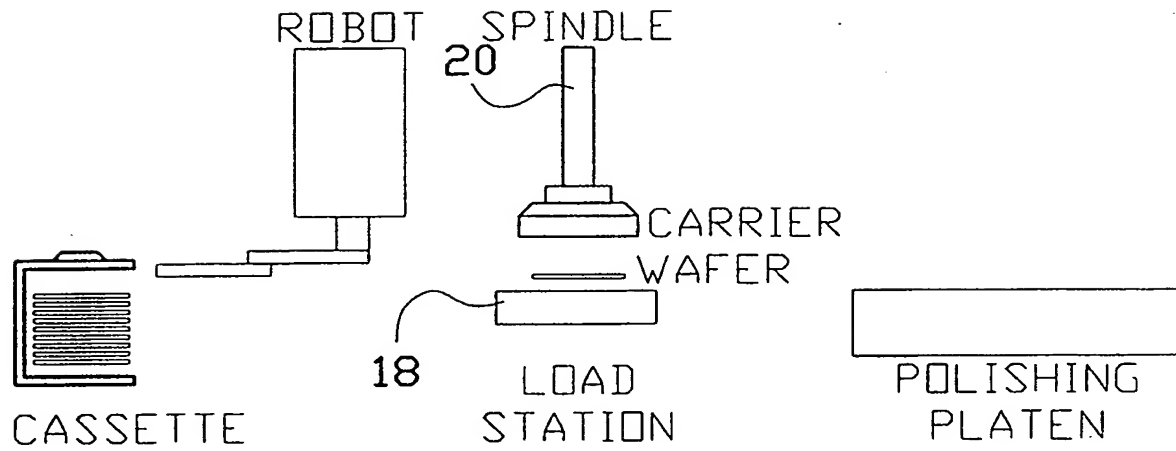


FIG. 3

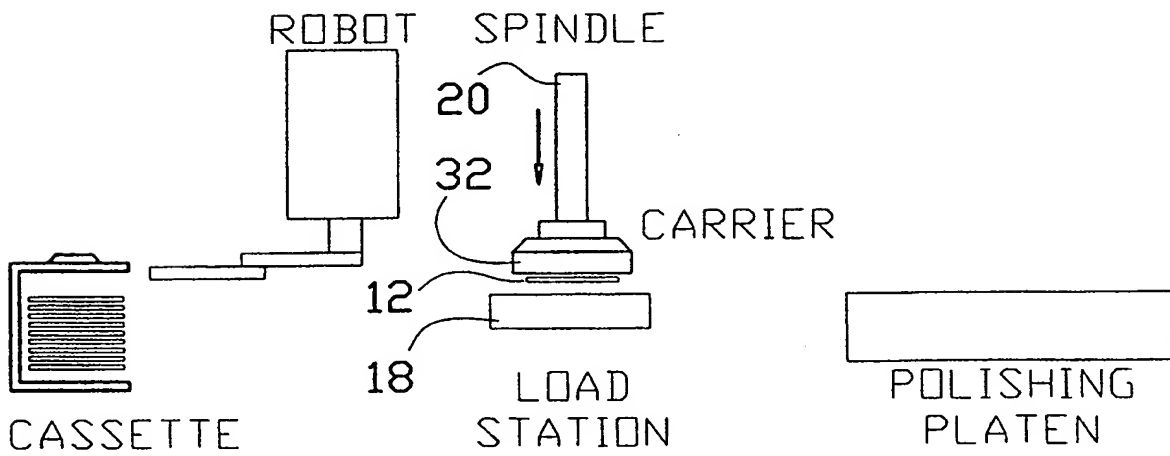


FIG. 4

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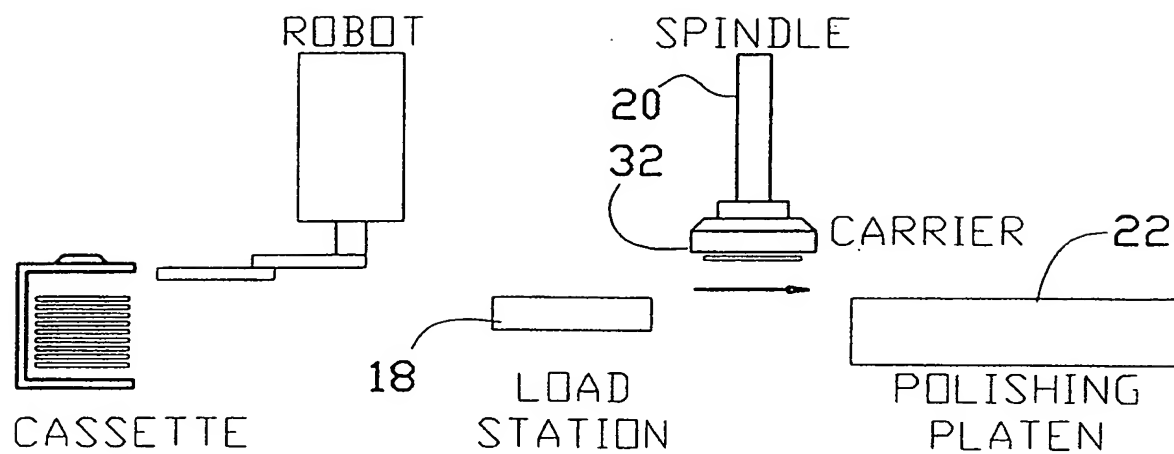


FIG. 5

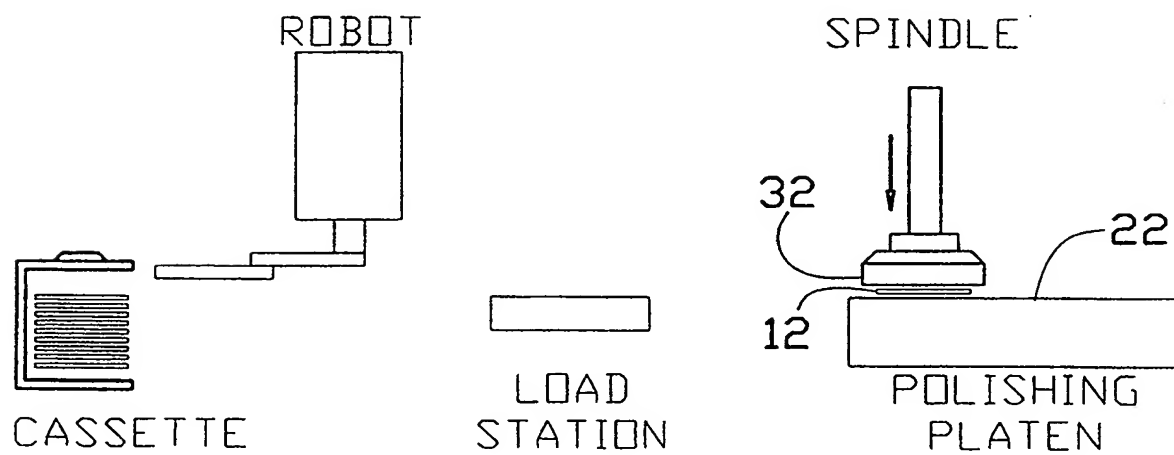


FIG. 6

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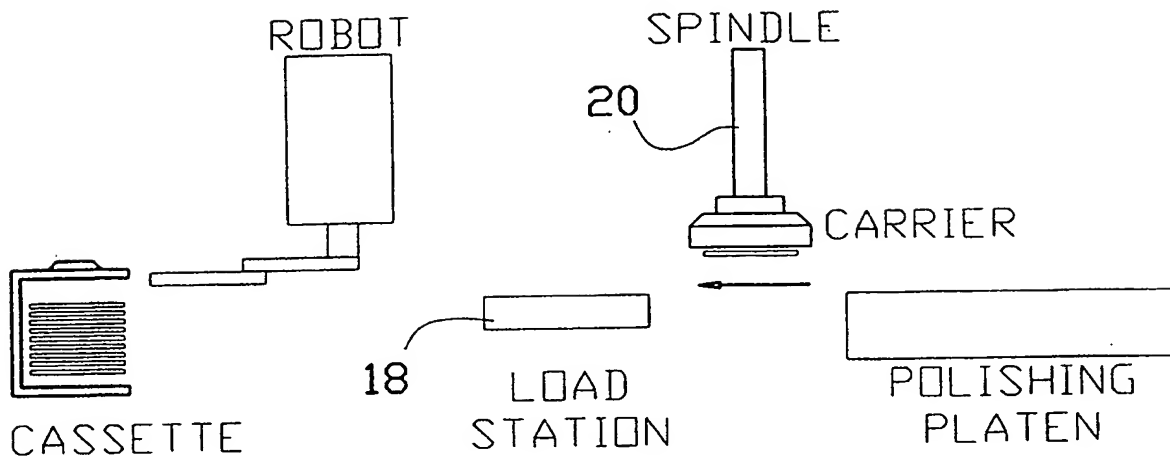


FIG. 7

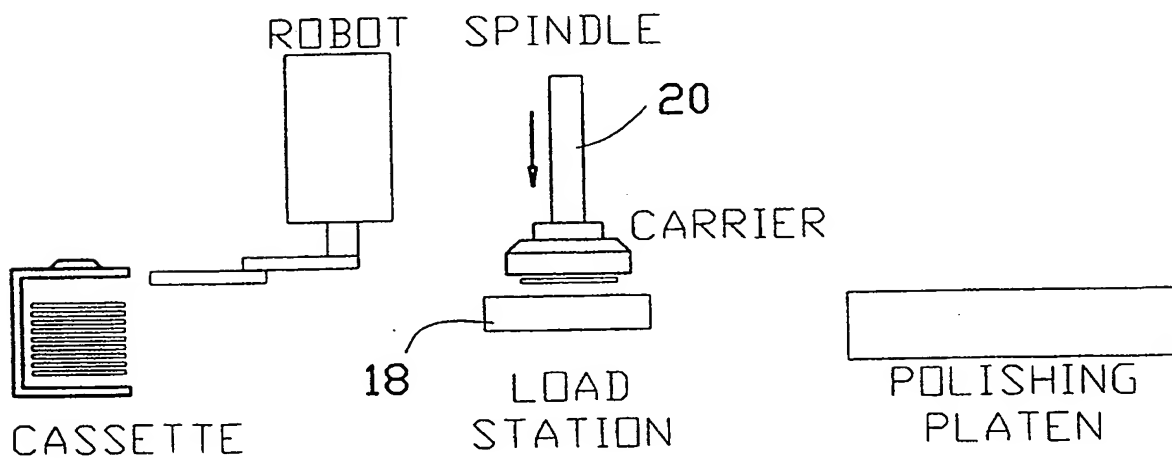


FIG. 8

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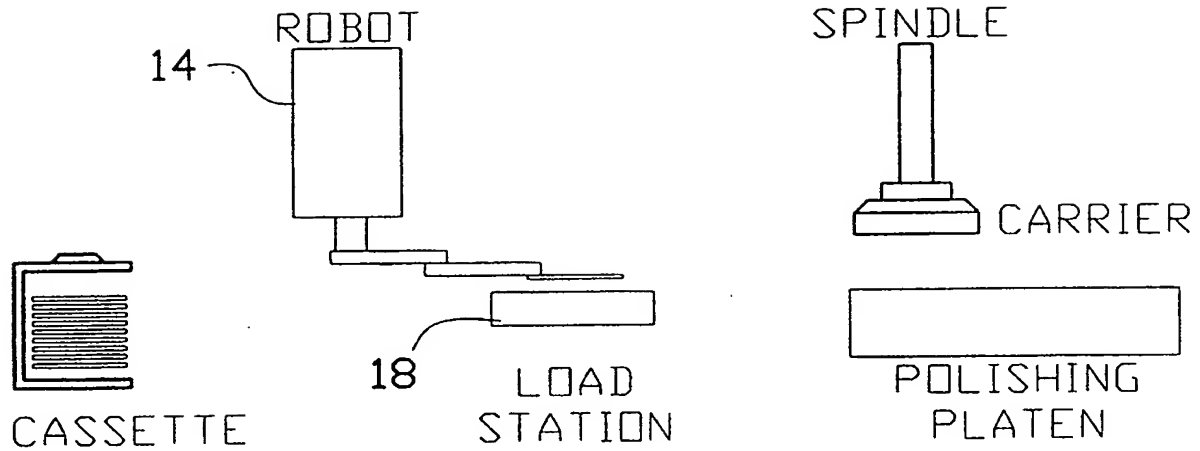


FIG. 9

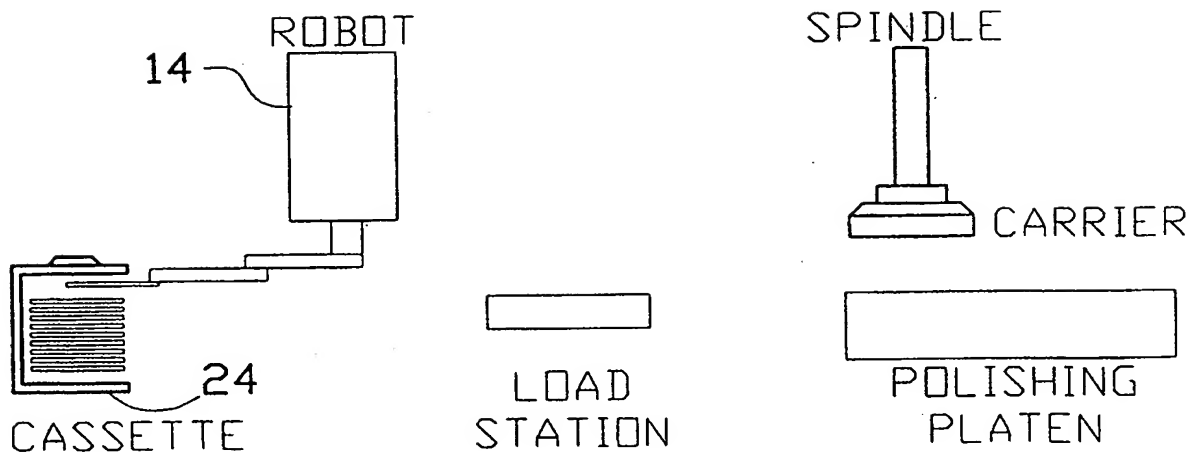
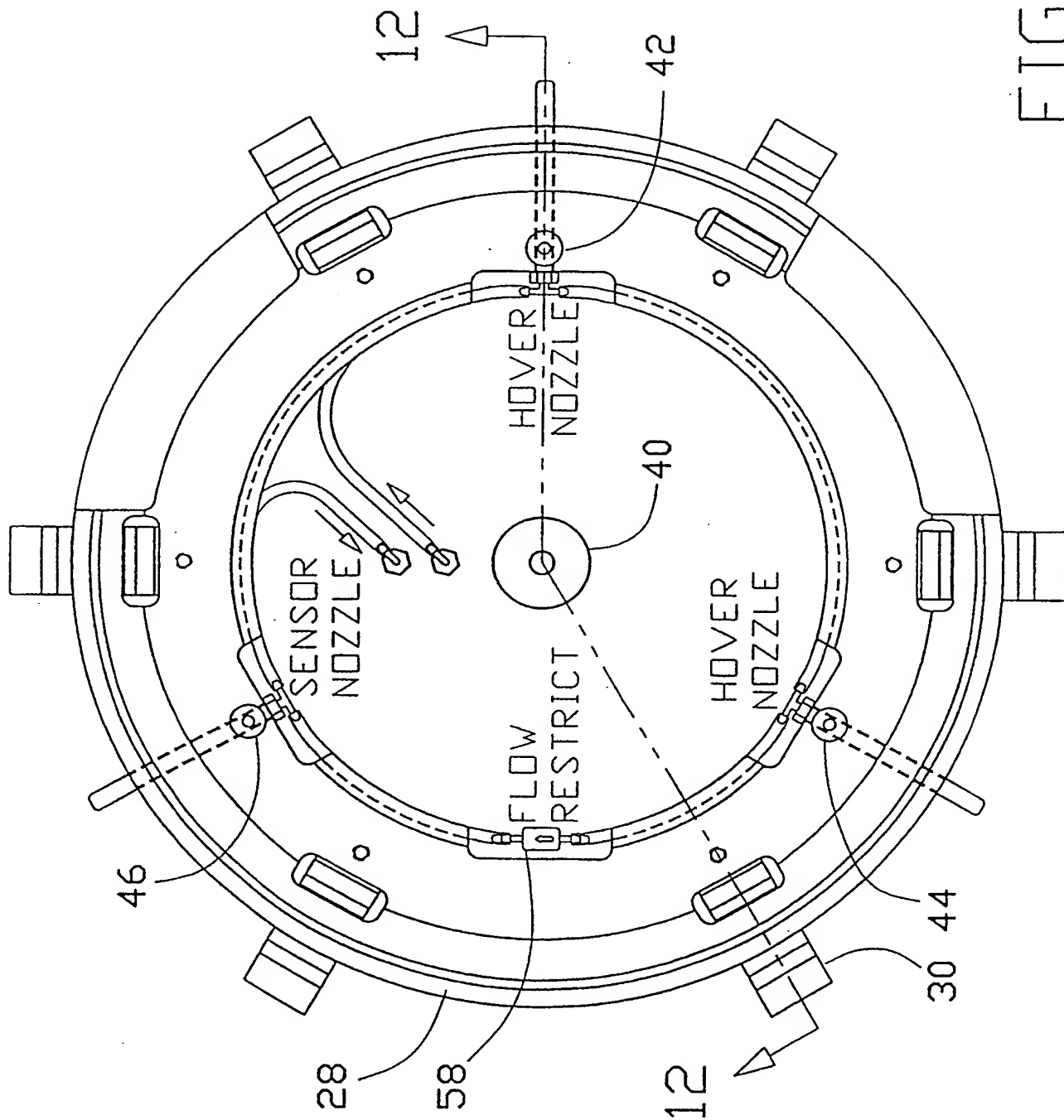


FIG. 10

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FIG. 11



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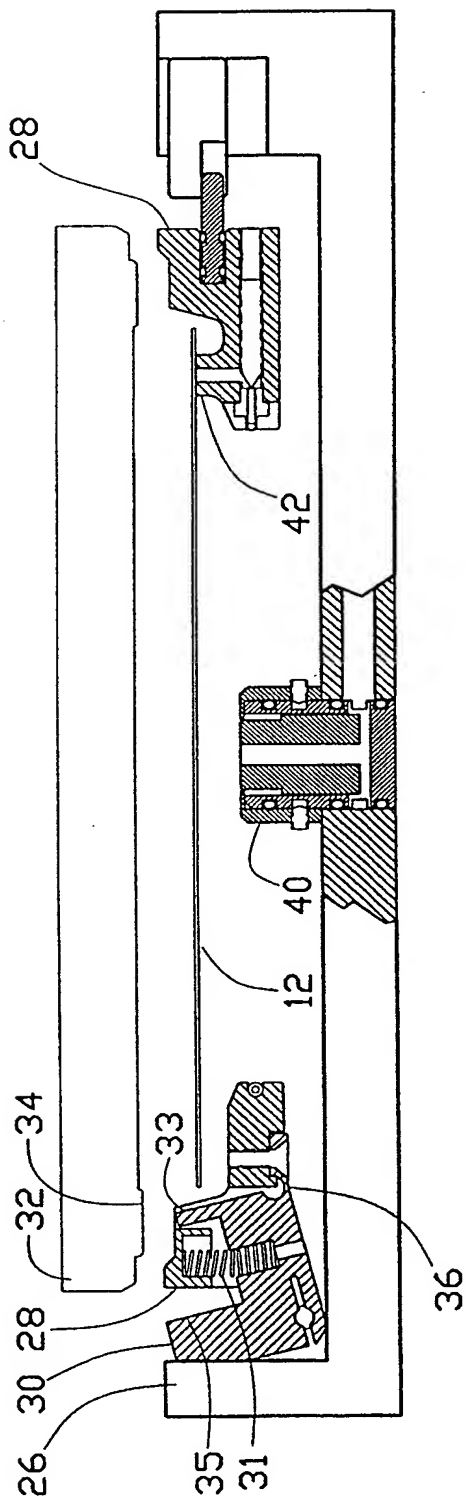


FIG. 12

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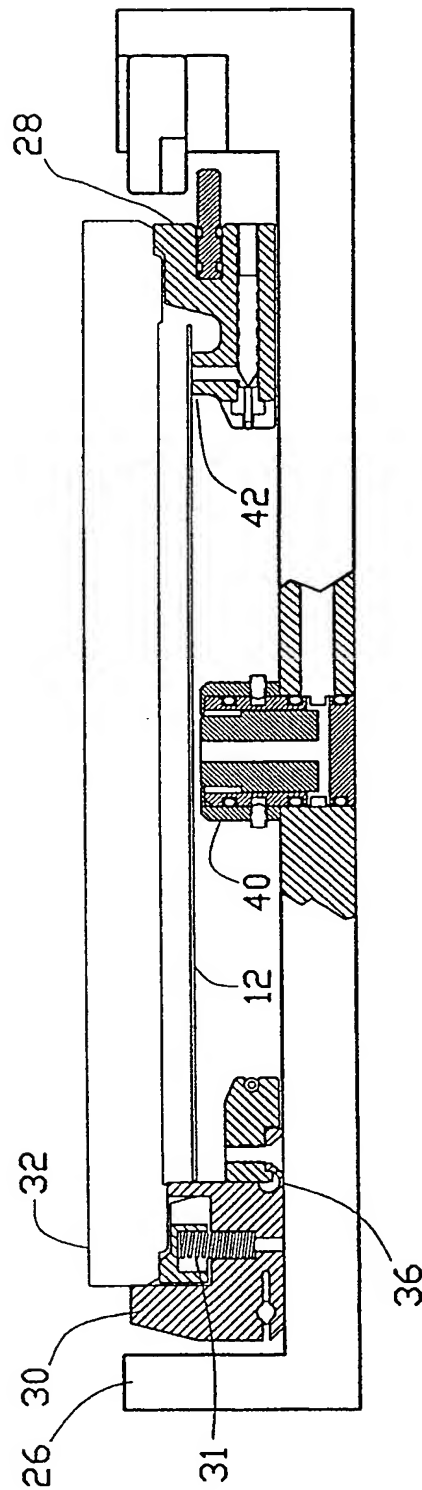


FIG. 13

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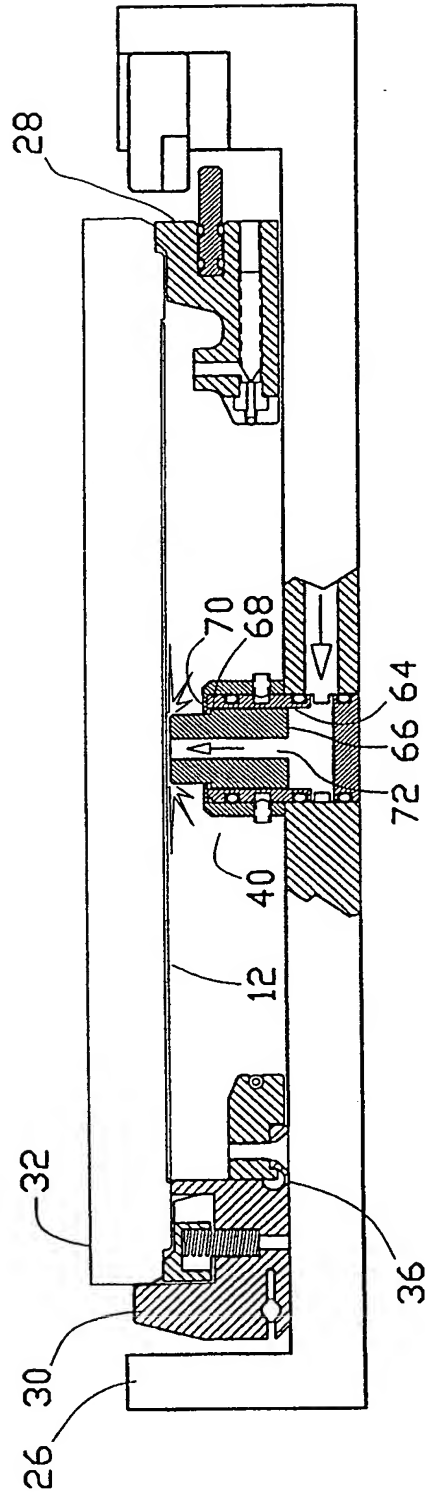


FIG. 14

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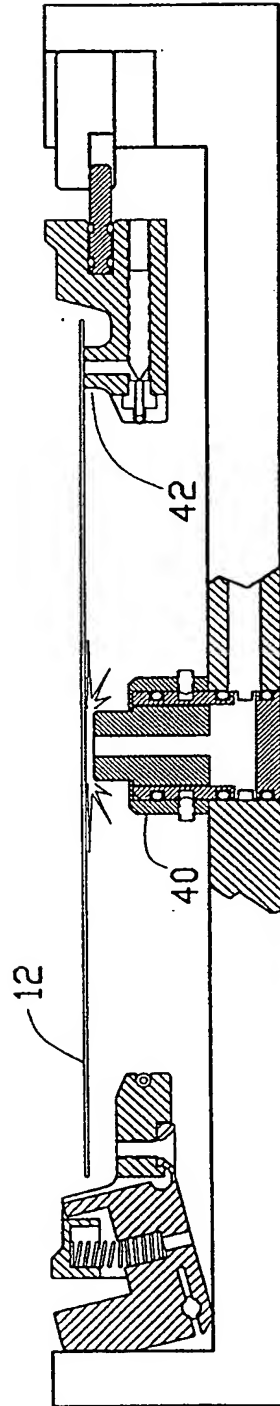


FIG. 15

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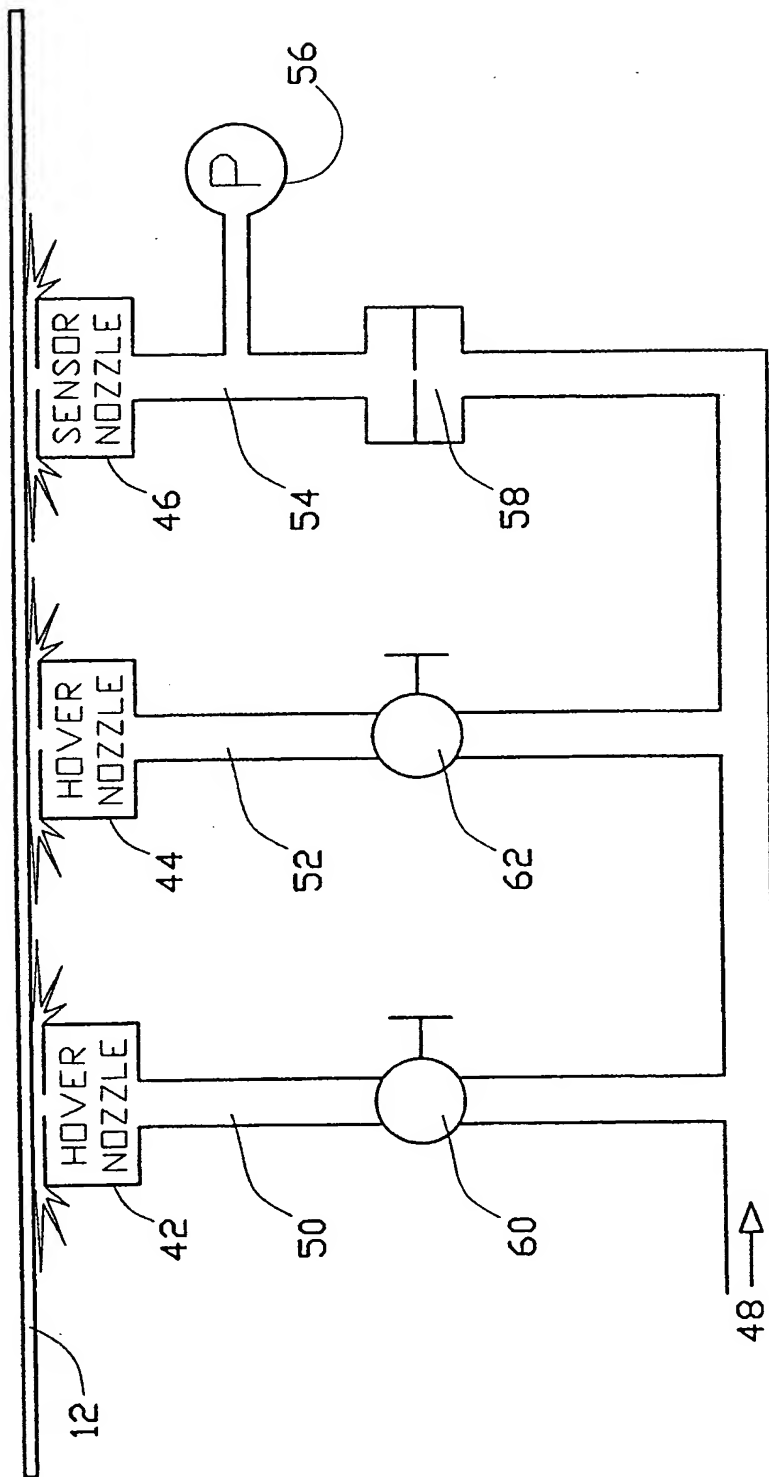


FIG. 16

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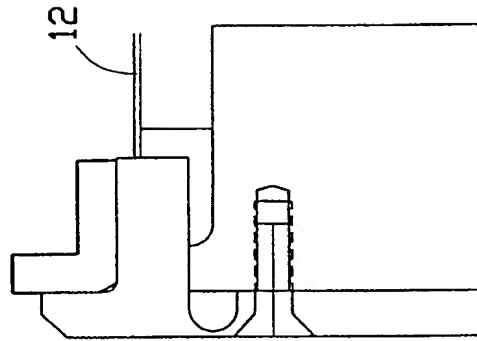


FIG. 18

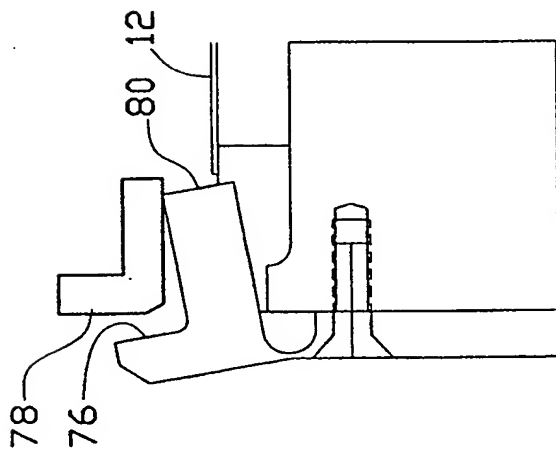


FIG. 17

INTERNATIONAL SEARCH REPORT

International application No.
PCT/US99/02699

A. CLASSIFICATION OF SUBJECT MATTER

IPC(6) : B08B 3/04, 1/00

US CL : 134/56R, 902, 94.1

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

U.S. : 134/56R, 902, 94.1, 61, 85, 88, 138

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

APS

bernoulli, wafer positioning, planarizing

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	US 4,566,726 A (CORRENTI et al) 28 January 1986.	1-10
A	US 3,830,592 A (KATO et al) 20 August 1974.	1-10
A	US 5,054,991 A (KATO) 08 October 1991.	1-10
A	US 5,582,534 A (SHENDON et al) 10 December 1996.	1-10
Y,E	US 5,885,135 A (DESORCIE et al) 23 March 1999.	1-10
Y,P	US 5,738,574 A (TOLLES et al) 14 April 1998.	1-10



Further documents are listed in the continuation of Box C.



See patent family annex.

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L document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)	*Z* document member of the same patent family
O document referring to an oral disclosure, use, exhibition or other means	
P document published prior to the international filing date but later than the priority date claimed	

Date of the actual completion of the international search

02 APRIL 1999

Date of mailing of the international search report

11 MAY 1999

Name and mailing address of the ISA/US
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